



Traceability Japan TC Chapter Meeting Summary and Minutes

Japan Winter 2017 Meetings in conjunction with SEMICON Japan 2017

December 15, 2017, 10:00 – 12:00

Conference Tower, Tokyo Big Sight, Tokyo, Japan

TC Chapter Announcements

Next TC Chapter Meeting

TBD

Table 1 Meeting Attendees

Italics indicate virtual participants

Co-Chairs: Hirokazu Tsunobuchi (Keyence), Yoichi Iga (Toshiba)

SEMI Staff: Chie Yanagisawa

<i>Company</i>	<i>Last</i>	<i>First</i>	<i>Company</i>	<i>Last</i>	<i>First</i>
Toshiba	Iga	Yoichi	NIST - National Institute of Standards & Technology	Obeng	Yaw
Keyence	Tsunobuchi	Hirokazu			
Kumai Consulting	Kumai	Sadao	SEMI Japan	Yanagisawa	Chie

Table 2 Leadership Changes

<i>WG/TF/SC/TC Name</i>	<i>Previous Leader</i>	<i>New Leader</i>
Fiducial Mark Interoperability Task Force	Hirokazu Tsunobuchi	The task force was discharged.

Table 3 Committee Structure Changes

<i>Previous WG/TF/SC Name</i>	<i>New WG/TF/SC Name or Status Change</i>
Fiducial Mark Interoperability Task Force	The task force was under the Japan TC Chapters of I&C, PI&C, Silicon Wafers, Traceability, and former Assembly & Packaging. All of the TC Chapters agreed with the discharge of this task force.

Table 4 Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
#6203	Reapproval of SEMI T22-0212: "Specification for Traceability by Self Authentication Service Body and Authentication Service Body"	Passed as balloted
#6244	Reapproval of SEMI T10-0701 (Reapproved 0912): "Test Method For The Assessment Of 2d Data Matrix Direct Mark Quality"	Passed as balloted
#6246	Reapproval of SEMI T17-0706 (Reapproved 0812): "Specification Of Substrate Traceability"	Passed as balloted
#6247	Reapproval of SEMI T18-1106 (Reapproved 0812): "Specification of Parts And Components Traceability"	Passed as balloted

Table 4 Ballot Results

<i>Document #</i>	<i>Document Title</i>	<i>Committee Action</i>
#6293	Line Item Revision to SEMI T15-0812: “General Specification of Jig ID: Concept” with title change to “Specification for Jig ID: Concept”	
Line Item 1	Change nonconforming title	Passed as balloted
Line Item 2	Add section title to meet the requirement which is specified section 3.2 of Procedure Manual	Passed with editorial change

#1 **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

#2 **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.

Table 5 Activities Approved by the GCS between meetings of the TC Chapter

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
6293	SNARF and Ballot Submission	5 Year Review TF	Line Item Revision to SEMI T15-0812 “General Specification of Jig ID: Concept” with non-conforming title change to “Specification for Jig ID: Concept” - Approved and authorized for ballot in voting Cycle 8-2017 by GCS on 10/13/2017
6245	Withdrawal of SNARF	5 Year Review TF under NA TC Chapter	Reapproval of SEMI T15-0812, General Specification Of Jig Id: Concept - <i>Prepared by the 5 Year Review Task Force, under the Traceability North America TC Chapter. During the preparation of the ballot draft of Reapproval of SEMI T15-0812, it was found out that the document was originally developed by the Traceability Japan TC Chapter and also needs some corrections. So, a new SNARF for Line Item Revision to SEMI T15-0812 is proposed by the Japan TC Chapter as above.</i> - Approved by GCS on 10/13/2017

Table 6 Authorized Activities

Listing of all revised or new SNARF(s) approved by the Originating TC Chapter.

<i>#</i>	<i>Type</i>	<i>SC/TF/WG</i>	<i>Details</i>
None			

#1 SNARFs and TFOFs are available for review on the SEMI Web site at:

<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF>

Table 7 Authorized Ballots

<i>#</i>	<i>When</i>	<i>TF</i>	<i>Details</i>
None			

Table 8 SNARF(s) Granted a One-Year Extension

<i>#</i>	<i>TF</i>	<i>Title</i>	<i>Expiration Date</i>
None			

Table 9 SNARF(s) Abolished

<i>#</i>	<i>TF</i>	<i>Title</i>
None		

Table 10 Standard(s) to receive Inactive Status

<i>Standard Designation</i>	<i>Title</i>
None	

Table 11 New Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
None		

Table 12 Previous Meeting Action Items

<i>Item #</i>	<i>Assigned to</i>	<i>Details</i>
None		

1 Welcome, Reminders, and Introductions

Yoichi Iga (Toshiba) called the meeting to order at 10:00. The meeting reminders on antitrust issues, intellectual property issues and holding meetings with international attendance were reviewed. Attendees introduced themselves.

Attachment: 01_Required_Elements_Reg_20150327_E+J

2 Review of Previous Meeting Minutes

The TC Chapter reviewed the minutes of the previous meeting.

Motion: To approve the minutes of the previous meeting as written.

By / 2nd: Hirokazu Tsunobuchi (Keyence) / Sadao Kumai (Kumai Consulting)

Discussion: None

Vote: 2 in favor and 0 opposed. **Motion passed.**

Attachment: 02_161216_Minutes_Traceability-Japan_Final

3 Liaison Reports

3.1 Traceability North America TC Chapter

Obeng Yaw (NIST) reported for the Traceability North America TC Chapter as attached.

- Leadership
- Organizational Chart
- Meeting Information
- Ballot Results
- 5 Year Review
 - The following four documents, originated from North America, to be adjudicated at this Traceability Japan TC Chapter meeting on December 15, 2017
 - Document #6244 - Reapproval of SEMI T10-0701 (Reapproved 0912): “Test Method For The Assessment Of 2d Data Matrix Direct Mark Quality”



- Document #6293 - Line Item Revision to SEMI T15-0812: “General Specification of Jig ID: Concept” with title change to “Specification for Jig ID: Concept”
 - Document #6246 - Reapproval of SEMI T17-0706 (Reapproved 0812): “Specification Of Substrate Traceability”
 - Document #6247 - Reapproval of SEMI T18-1106 (Reapproved 0812): “Specification of Parts And Components Traceability”
- SNARF 3 Year Status
 - Task Force / Working Group Reports

Attachment: 03_NA Liaison Report - Traceability July 2017_v2

3.2 SEMI Staff Report

Chie Yanagisawa (SEMI Japan) gave the SEMI Staff Report. Of note:

- SEMI Global 2017/2018 Calendar of Events
- Global Standards Meeting Schedule
- SEMICON Japan Overview
- SEMICON Japan Standards Meetings
- 2017/2018 Critical Dates for SEMI Standards Ballots
- A&R Ballot Review
- SEMI Standards Publications
- JRSC Topics
- SEMI Japan Newsletter

Attachment: 04_SEMI Staff Report 20171212c

4 Ballot Review

NOTE 1: TC Chapter adjudication on ballots reviewed is detailed in the Audits & Review (A&R) Subcommittee Forms for procedural review. The A&R forms are available as attachments to these minutes. The attachment number for each balloted document is provided under each ballot review section below.

4.1 Document #6203 - Reapproval of SEMI T22-0212: “Specification for Traceability by Self Authentication Service Body and Authentication Service Body”

Attachment: 05_LetterBallotReviewSheet_#6203_T22-Reapproval

4.2 Document #6244 - Reapproval of SEMI T10-0701 (Reapproved 0912): “Test Method For The Assessment Of 2d Data Matrix Direct Mark Quality”

Attachment: 06_LetterBallotReviewSheet_#6244_T10-Reapproval

4.3 Document #6246 - Reapproval of SEMI T17-0706 (Reapproved 0812): “Specification Of Substrate Traceability”

Attachment: 07_LetterBallotReviewSheet_#6246_T17-Reapproval

4.4 Document #6247 - Reapproval of SEMI T18-1106 (Reapproved 0812): “Specification of Parts And Components Traceability”

Attachment: 08_LetterBallotReviewSheet_#6247_T18-Reapproval

4.5 Document #6293 - Line Item Revision to SEMI T15-0812: “General Specification of Jig ID: Concept” with title change to “Specification for Jig ID: Concept”

4.5.1 Line Item 1 - Change nonconforming title

4.5.2 Line Item 2 - Add section title to meet the requirement which is specified section 3.2 of Procedure Manual

Attachment: 09_LetterBallotReviewSheet_#6293_T15-LIRevision

5 Subcommittee and Task Force Reports

5.1 5 Year Review Task Force

Hirokazu Tsunobuchi (Keyence) reported for the 5 Year Review Task Force as follows.

- The following two documents were reviewed and passed as balloted at the “Ballot Review” section above.
 - Document #6203 - Reapproval of SEMI T22-0212: “Specification for Traceability by Self Authentication Service Body and Authentication Service Body”
 - Document #6293 - Line Item Revision to SEMI T15-0812: “General Specification of Jig ID: Concept” with title change to “Specification for Jig ID: Concept”

5.2 Fiducial Mark Interoperability Task Force

Hirokazu Tsunobuchi (Keyence) reported for the Fiducial Mark Interoperability Task Force as follows.

- The latest TF meeting on Nov. 18, 2015
- Disbandment of this TF
 - TF leaders decided to propose disbanding this TF to each technical committee
 - The Silicon Wafers Japan TC Chapter agreed on March 9, 2017, former Assembly & Packaging Japan TC Chapter agreed on March 13, 2017, PI&C Japan TC Chapter agreed on April 19, 2017 and the I&C Japan TC Chapter agreed on April 21, 2017.
 - To be proposed at this Japan TC Chapter meeting at “New Business” section.
- Backend alignment issues with introducing fiducial mark wafer is left.
 - Would be discussed in 3D Packaging & Integration (former Assembly & Packaging) Japan TC Chapter after its disbandment.

6 Old Business

6.1 5 Year Review Check

Hirokazu Tsunobuchi (Keyence) addressed the committee on this topic.

The following document is the oldest originated by Japan TC Chapter.

- SEMI T21-0314: Specification for Organization Identification by Digital Certificate Issued from Certificate Service Body (CSB) for Anti-Counterfeiting Traceability in Components Supply Chain

6.2 SNARF Project Period Check

Chie Yanagisawa (SEMI Japan) addressed the committee on this topic. There are only two SNARFs currently and the documents just passed at this TC Chapter meeting.

- SNARF for Reapproval of SEMI T22 was approved in December 2016
- SNARF for Line Item Revision to SEMI T15 was approved in October 2017

7 New Business

7.1 Discharge of Fiducial Mark Interoperability Task Force

Hirokazu Tsunobuchi (Keyence) addressed the committee on this topic.

Motion: To approve the disbandment of the Fiducial Mark Interoperability Task Force
By / 2nd: Hirokazu Tsunobuchi (Keyence) / Sadao Kumai (Kumai Consulting)
Discussion: None
Vote: 3 in favor and 0 opposed. **Motion Passed.**

7.2 Discussion of Cybersecurity

Obeng Yaw (NIST) addressed the committee on this topic and explained the cybersecurity framework concepts as shown in the attached materials.

The TC chapter will study the materials and consult with technical experts and decide on direction.

Attachment: 10_Implementation of NIST Cybersecurity Framework, 11_NIST Cybersecurity framework_update_20170301

8 Next Meeting and Adjournment

The next meeting is to be decided. See <http://www.semi.org/standards-events> in future.

Adjournment: 12:00.



Respectfully submitted by:

Chie Yanagisawa

Manager

SEMI Japan

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Minutes tentatively approved by:

Yoichi Iga (Toshiba), Co-chair	June 22, 2018
Hirokazu Tsunobuchi (Keyence), Co-chair	June 22, 2018

Table 13 Index of Available Attachments^{#1}

<i>Title</i>	<i>Title</i>
01_Required_Elements_Reg_20150327_E+J	07_LetterBallotReviewSheet_#6246_T17-Reapproval
02_161216_Minutes_Traceability-Japan_Final	08_LetterBallotReviewSheet_#6247_T18-Reapproval
03_NA Liaison Report - Traceability July 2017_v2	09_LetterBallotReviewSheet_#6293_T15-LIRrevision
04_SEMI Staff Report 20171212c	10_Implementation of NIST Cybersecurity Framework
05_LetterBallotReviewSheet_#6203_T22-Reapproval	11_NIST Cybersecurity framework_update_20170301
06_LetterBallotReviewSheet_#6244_T10-Reapproval	

^{#1} Due to file size and delivery issues, attachments must be downloaded separately. A .zip file containing all attachments for these minutes is available at www.semi.org. For additional information or to obtain individual attachments, please contact [SEMI Staff Name] at the contact information above.